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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	516096
Number of I/O	341
Number of Gates	3000000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/m1a3pe3000-2fgg484i

Temperature Grade Offerings

Package	A3PE600	A3PE1500	A3PE3000
Cortex-M1 Devices		M1A3PE1500	M1A3PE3000
PQ208	C, I	C, I	C, I
FG256	C, I	–	–
FG324	–	–	C, I
FG484	C, I	C, I	C, I
FG676	–	C, I	–
FG896	–	–	C, I

Note: C = Commercial temperature range: 0°C to 70°C ambient temperature
 I = Industrial temperature range: –40°C to 85°C ambient temperature

Speed Grade and Temperature Grade Matrix

Temperature Grade	Std.	–1	–2
C ¹	✓	✓	✓
I ²	✓	✓	✓

Notes:

1. C = Commercial temperature range: 0°C to 70°C ambient temperature
2. I = Industrial temperature range: –40°C to 85°C ambient temperature

References made to ProASIC3E devices also apply to ARM-enabled ProASIC3E devices. The ARM-enabled part numbers start with M1 (Cortex-M1).

Contact your local Microsemi SoC Products Group representative for device availability:
www.microsemi.com/index.php?option=com_content&id=135&lang=en&view=article.

Single Chip

Flash-based FPGAs store their configuration information in on-chip flash cells. Once programmed, the configuration data is an inherent part of the FPGA structure, and no external configuration data needs to be loaded at system power-up (unlike SRAM-based FPGAs). Therefore, flash-based ProASIC3E FPGAs do not require system configuration components such as EEPROMs or microcontrollers to load device configuration data. This reduces bill-of-materials costs and PCB area, and increases security and system reliability.

Instant On

Flash-based ProASIC3E devices support Level 0 of the Instant On classification standard. This feature helps in system component initialization, execution of critical tasks before the processor wakes up, setup and configuration of memory blocks, clock generation, and bus activity management. The Instant On feature of flash-based ProASIC3E devices greatly simplifies total system design and reduces total system cost, often eliminating the need for CPLDs and clock generation PLLs that are used for these purposes in a system. In addition, glitches and brownouts in system power will not corrupt the ProASIC3E device's flash configuration, and unlike SRAM-based FPGAs, the device will not have to be reloaded when system power is restored. This enables the reduction or complete removal of the configuration PROM, expensive voltage monitor, brownout detection, and clock generator devices from the PCB design. Flash-based ProASIC3E devices simplify total system design and reduce cost and design risk while increasing system reliability and improving system initialization time.

Firm Errors

Firm errors occur most commonly when high-energy neutrons, generated in the upper atmosphere, strike a configuration cell of an SRAM FPGA. The energy of the collision can change the state of the configuration cell and thus change the logic, routing, or I/O behavior in an unpredictable way. These errors are impossible to prevent in SRAM FPGAs. The consequence of this type of error can be a complete system failure. Firm errors do not exist in the configuration memory of ProASIC3E flash-based FPGAs. Once it is programmed, the flash cell configuration element of ProASIC3E FPGAs cannot be altered by high-energy neutrons and is therefore immune to them. Recoverable (or soft) errors occur in the user data SRAM of all FPGA devices. These can easily be mitigated by using error detection and correction (EDAC) circuitry built into the FPGA fabric.

Low Power

Flash-based ProASIC3E devices exhibit power characteristics similar to an ASIC, making them an ideal choice for power-sensitive applications. ProASIC3E devices have only a very limited power-on current surge and no high-current transition period, both of which occur on many FPGAs.

ProASIC3E devices also have low dynamic power consumption to further maximize power savings.

Advanced Flash Technology

The ProASIC3E family offers many benefits, including nonvolatility and reprogrammability through an advanced flash-based, 130-nm LVCMOS process with seven layers of metal. Standard CMOS design techniques are used to implement logic and control functions. The combination of fine granularity, enhanced flexible routing resources, and abundant flash switches allows for very high logic utilization without compromising device routability or performance. Logic functions within the device are interconnected through a four-level routing hierarchy.

Calculating Power Dissipation

Quiescent Supply Current

Table 2-7 • Quiescent Supply Current Characteristics

	A3PE600	A3PE1500	A3PE3000
Typical (25°C)	5 mA	12 mA	25 mA
Maximum (Commercial)	30 mA	70 mA	150 mA
Maximum (Industrial)	45 mA	105 mA	225 mA

Notes:

1. *IDD* Includes *VCC*, *VPUMP*, *VCCI*, and *VMV* currents. Values do not include I/O static contribution, which is shown in [Table 2-8](#) and [Table 2-9](#) on [page 2-7](#).
2. *-F* speed grade devices may experience higher standby *IDD* of up to five times the standard *IDD* and higher I/O leakage.

Power per I/O Pin

Table 2-8 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings

	VMV (V)	Static Power PDC2 (mW) ¹	Dynamic Power PAC9 (μW/MHz) ²
Single-Ended			
3.3 V LVTTTL/LVCMOS	3.3	–	17.39
3.3 V LVTTTL/LVCMOS – Schmitt trigger	3.3	–	25.51
3.3 V LVTTTL/LVCMOS Wide Range ³	3.3	–	16.34
3.3 V LVTTTL/LVCMOS Wide Range – Schmitt trigger ³	3.3	–	24.49
2.5 V LVCMOS	2.5	–	5.76
2.5 V LVCMOS – Schmitt trigger	2.5	–	7.16
1.8 V LVCMOS	1.8	–	2.72
1.8 V LVCMOS – Schmitt trigger	1.8	–	2.80
1.5 V LVCMOS (JESD8-11)	1.5	–	2.08
1.5 V LVCMOS (JESD8-11) – Schmitt trigger	1.5	–	2.00
3.3 V PCI	3.3	–	18.82
3.3 V PCI – Schmitt trigger	3.3	–	20.12
3.3 V PCI-X	3.3	–	18.82
3.3 V PCI-X – Schmitt trigger	3.3	–	20.12
Voltage-Referenced			
3.3 V GTL	3.3	2.90	8.23
2.5 V GTL	2.5	2.13	4.78
3.3 V GTL+	3.3	2.81	4.14
2.5 V GTL+	2.5	2.57	3.71

Notes:

1. *PDC2* is the static power (where applicable) measured on *VMV*.
2. *PAC9* is the total dynamic power measured on *VCC* and *VMV*.
3. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD8b specification.

Combinatorial Cells Contribution— P_{C-CELL}

$$P_{C-CELL} = N_{C-CELL} * \alpha_1 / 2 * PAC7 * F_{CLK}$$

N_{C-CELL} is the number of VersaTiles used as combinatorial modules in the design.

α_1 is the toggle rate of VersaTile outputs—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

Routing Net Contribution— P_{NET}

$$P_{NET} = (N_{S-CELL} + N_{C-CELL}) * \alpha_1 / 2 * PAC8 * F_{CLK}$$

N_{S-CELL} is the number of VersaTiles used as sequential modules in the design.

N_{C-CELL} is the number of VersaTiles used as combinatorial modules in the design.

α_1 is the toggle rate of VersaTile outputs—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

I/O Input Buffer Contribution— P_{INPUTS}

$$P_{INPUTS} = N_{INPUTS} * \alpha_2 / 2 * PAC9 * F_{CLK}$$

N_{INPUTS} is the number of I/O input buffers used in the design.

α_2 is the I/O buffer toggle rate—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

I/O Output Buffer Contribution— $P_{OUTPUTS}$

$$P_{OUTPUTS} = N_{OUTPUTS} * \alpha_2 / 2 * \beta_1 * PAC10 * F_{CLK}$$

$N_{OUTPUTS}$ is the number of I/O output buffers used in the design.

α_2 is the I/O buffer toggle rate—guidelines are provided in [Table 2-11 on page 2-11](#).

β_1 is the I/O buffer enable rate—guidelines are provided in [Table 2-12 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

RAM Contribution— P_{MEMORY}

$$P_{MEMORY} = PAC11 * N_{BLOCKS} * F_{READ-CLOCK} * \beta_2 + PAC12 * N_{BLOCK} * F_{WRITE-CLOCK} * \beta_3$$

N_{BLOCKS} is the number of RAM blocks used in the design.

$F_{READ-CLOCK}$ is the memory read clock frequency.

β_2 is the RAM enable rate for read operations—guidelines are provided in [Table 2-12 on page 2-11](#).

$F_{WRITE-CLOCK}$ is the memory write clock frequency.

β_3 is the RAM enable rate for write operations—guidelines are provided in [Table 2-12 on page 2-11](#).

PLL Contribution— P_{PLL}

$$P_{PLL} = PAC13 + PAC14 * F_{CLKOUT}$$

F_{CLKOUT} is the output clock frequency.¹

1. The PLL dynamic contribution depends on the input clock frequency, the number of output clock signals generated by the PLL, and the frequency of each output clock. If a PLL is used to generate more than one output clock, include each output clock in the formula by adding its corresponding contribution ($PAC14 * F_{CLKOUT}$ product) to the total PLL contribution.

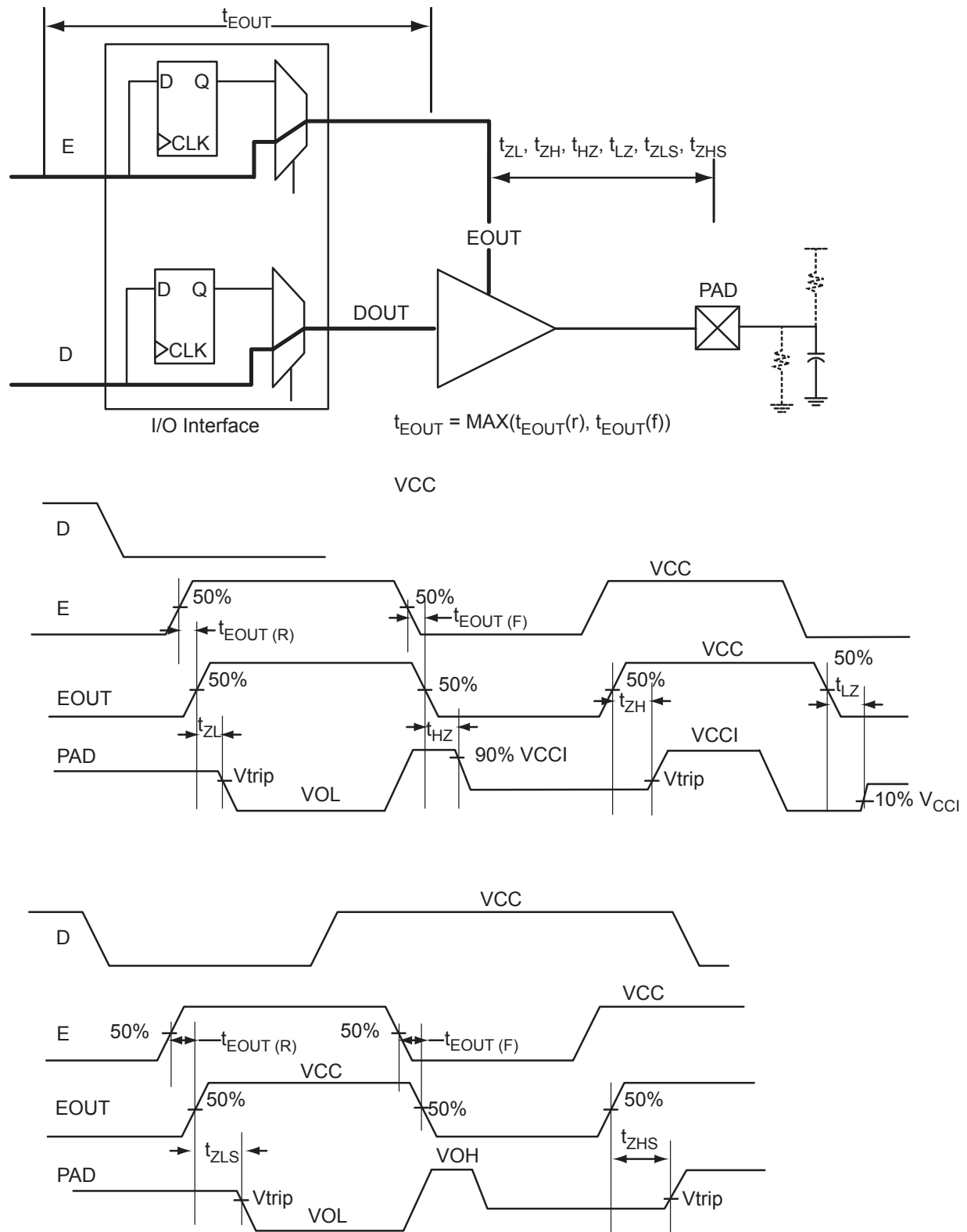


Figure 2-5 • Tristate Output Buffer Timing Model and Delays (example)

Table 2-14 • Summary of Maximum and Minimum DC Input Levels
Applicable to Commercial and Industrial Conditions

DC I/O Standards	Commercial ¹		Industrial ²	
	IIL ³	IIH ⁴	IIL ³	IIH ⁴
	μA	μA	μA	μA
3.3 V LVTTTL / 3.3 V LVCMOS	10	10	15	15
3.3 V LVCMOS Wide Range	10	10	15	15
2.5 V LVCMOS	10	10	15	15
1.8 V LVCMOS	10	10	15	15
1.5 V LVCMOS	10	10	15	15
3.3 V PCI	10	10	15	15
3.3 V PCI-X	10	10	15	15
3.3 V GTL	10	10	15	15
2.5 V GTL	10	10	15	15
3.3 V GTL+	10	10	15	15
2.5 V GTL+	10	10	15	15
HSTL (I)	10	10	15	15
HSTL (II)	10	10	15	15
SSTL2 (I)	10	10	15	15
SSTL2 (II)	10	10	15	15
SSTL3 (I)	10	10	15	15
SSTL3 (II)	10	10	15	15

Notes:

1. Commercial range ($0^{\circ}\text{C} < T_A < 70^{\circ}\text{C}$)
2. Industrial range ($-40^{\circ}\text{C} < T_A < 85^{\circ}\text{C}$)
3. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3\text{ V} < V_{IN} < V_{IL}$.
4. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.

1.5 V LVCMOS (JESD8-11)

Low-Voltage CMOS for 1.5 V is an extension of the LVCMOS standard (JESD8-5) used for general-purpose 1.5 V applications. It uses a 1.5 V input buffer and a push-pull output buffer.

Table 2-41 • Minimum and Maximum DC Input and Output Levels

1.5 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
2 mA	−0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	2	2	16	13	10	10
4 mA	−0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	4	4	33	25	10	10
6 mA	−0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	6	6	39	32	10	10
8 mA	−0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	8	8	55	66	10	10
12 mA	−0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	12	12	55	66	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3\text{ V} < V_{IN} < V_{IL}$.
2. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.
5. Software default selection highlighted in gray.

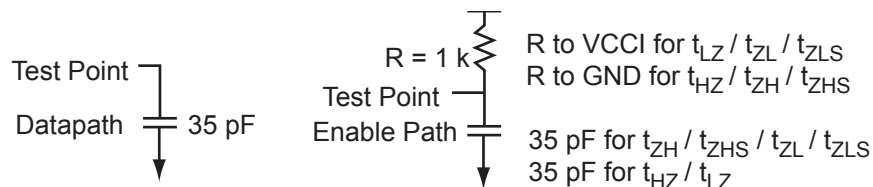


Figure 2-10 • AC Loading

Table 2-42 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	C _{LOAD} (pF)
0	1.5	0.75	—	35

Note: *Measuring point = Vtrip. See Table 2-15 on page 2-18 for a complete table of trip points.

HSTL Class II

High-Speed Transceiver Logic is a general-purpose high-speed 1.5 V bus standard (EIA/JESD8-6). ProASIC3E devices support Class II. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-63 • Minimum and Maximum DC Input and Output Levels

HSTL Class II	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
15 mA ³	−0.3	VREF − 0.1	VREF + 0.1	3.6	0.4	VCCI − 0.4	15	15	55	66	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 85°C junction temperature.
3. Output drive strength is below JEDEC specification.

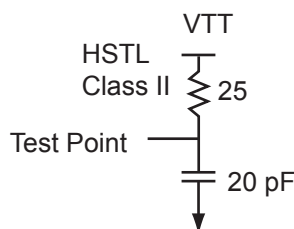


Figure 2-17 • AC Loading

Table 2-64 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF − 0.1	VREF + 0.1	0.75	0.75	0.75	20

Note: *Measuring point = Vtrip. See [Table 2-15 on page 2-18](#) for a complete table of trip points.

Timing Characteristics

Table 2-65 • HSTL Class II

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V,
Worst-Case VCCI = 1.4 V, VREF = 0.75 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.66	3.02	0.04	2.12	0.43	3.08	2.71			5.32	4.95	ns
−1	0.56	2.57	0.04	1.81	0.36	2.62	2.31			4.52	4.21	ns
−2	0.49	2.26	0.03	1.59	0.32	2.30	2.03			3.97	3.70	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-5](#) for derating values.

SSTL2 Class I

Stub-Speed Terminated Logic for 2.5 V memory bus standard (JESD8-9). ProASIC3E devices support Class I. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-66 • Minimum and Maximum DC Input and Output Levels

SSTL2 Class I	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
15 mA	-0.3	VREF - 0.2	VREF + 0.2	3.6	0.54	VCCI - 0.62	15	15	87	83	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 85°C junction temperature.

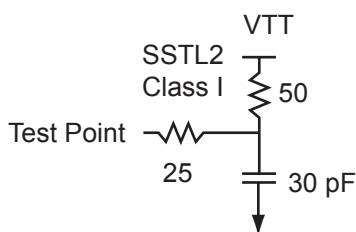


Figure 2-18 • AC Loading

Table 2-67 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF - 0.2	VREF + 0.2	1.25	1.25	1.25	30

Note: *Measuring point = Vtrip. See Table 2-15 on page 2-18 for a complete table of trip points.

Timing Characteristics

Table 2-68 • SSTL 2 Class I

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V, VREF = 1.25 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.66	2.13	0.04	1.33	0.43	2.17	1.85			4.40	4.08	ns
-1	0.56	1.81	0.04	1.14	0.36	1.84	1.57			3.74	3.47	ns
-2	0.49	1.59	0.03	1.00	0.32	1.62	1.38			3.29	3.05	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-5 for derating values.

SSTL2 Class II

Stub-Speed Terminated Logic for 2.5 V memory bus standard (JESD8-9). ProASIC3E devices support Class II. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-69 • Minimum and Maximum DC Input and Output Levels

SSTL2 Class II	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
18 mA	−0.3	VREF − 0.2	VREF + 0.2	3.6	0.35	VCCI − 0.43	18	18	124	169	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 85°C junction temperature.

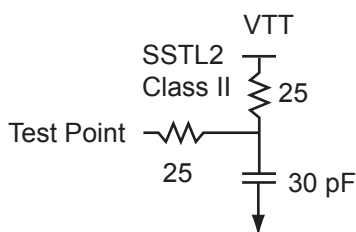


Figure 2-19 • AC Loading

Table 2-70 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF − 0.2	VREF + 0.2	1.25	1.25	1.25	30

Note: *Measuring point = Vtrip. See Table 2-15 on page 2-18 for a complete table of trip points.

Timing Characteristics

Table 2-71 • SSTL 2 Class II

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V, VREF = 1.25 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.66	0.66	2.17	0.04	1.33	0.43	2.21	1.77			4.44	ns
−1	0.56	0.56	1.84	0.04	1.14	0.36	1.88	1.51			3.78	ns
−2	0.49	0.49	1.62	0.03	1.00	0.32	1.65	1.32			3.32	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-5 for derating values.

SSTL3 Class II

Stub-Speed Terminated Logic for 3.3 V memory bus standard (JESD8-8). ProASIC3E devices support Class II. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-75 • Minimum and Maximum DC Input and Output Levels

SSTL3 Class II	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
21 mA	−0.3	VREF − 0.2	VREF + 0.2	3.6	0.5	VCCI − 0.9	21	21	109	103	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 85°C junction temperature.

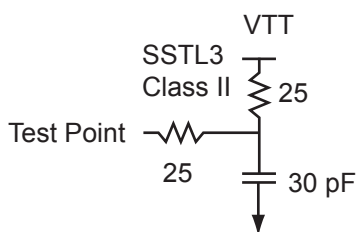


Figure 2-21 • AC Loading

Table 2-76 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF − 0.2	VREF + 0.2	1.5	1.5	1.485	30

Note: *Measuring point = V_{trip}. See [Table 2-15 on page 2-18](#) for a complete table of trip points.

Timing Characteristics

Table 2-77 • SSTL3 Class II

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V,
Worst-Case VCCI = 3.0 V, VREF = 1.5 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.66	2.07	0.04	1.25	0.43	2.10	1.67			4.34	3.91	ns
−1	0.56	1.76	0.04	1.06	0.36	1.79	1.42			3.69	3.32	ns
−2	0.49	1.54	0.03	0.93	0.32	1.57	1.25			3.24	2.92	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-5](#) for derating values.

DDR Module Specifications

Input DDR Module

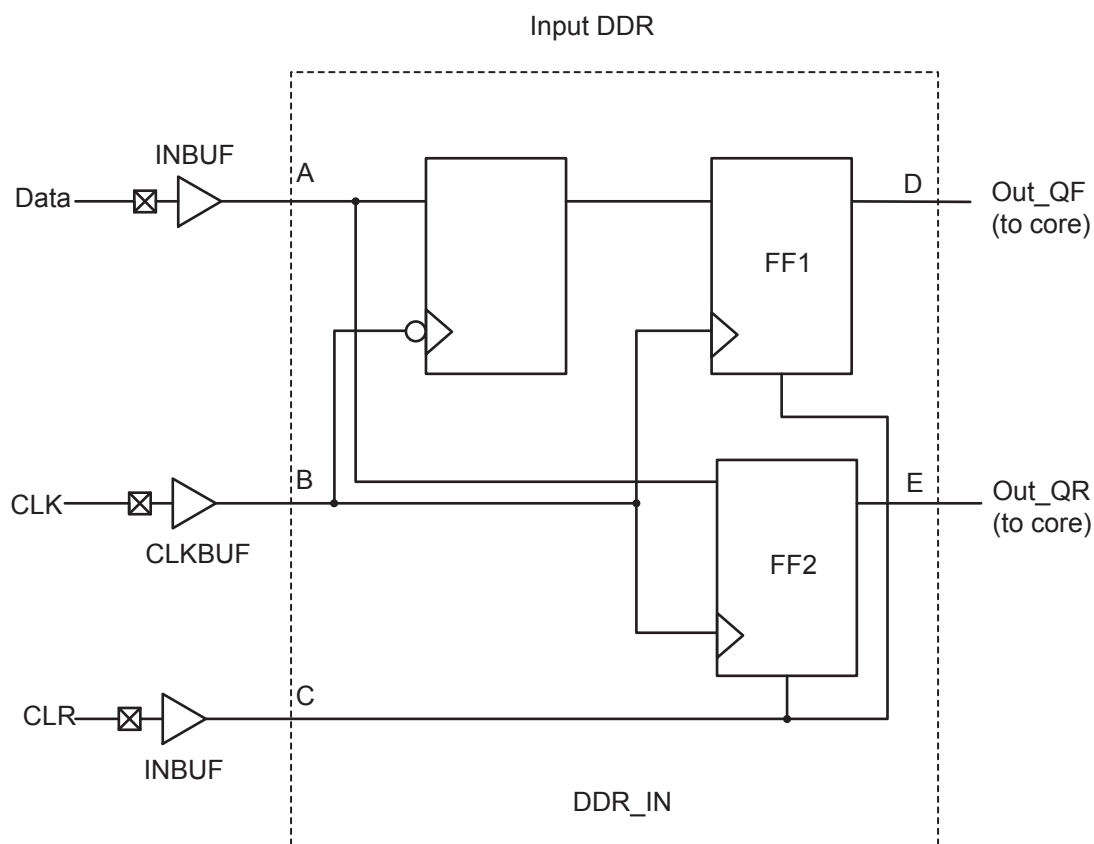


Figure 2-30 • Input DDR Timing Model

Table 2-89 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
$t_{DDRICKQ1}$	Clock-to-Out Out_QR	B, D
$t_{DDRICKQ2}$	Clock-to-Out Out_QF	B, E
$t_{DDRISUD}$	Data Setup Time of DDR input	A, B
t_{DDRIHD}	Data Hold Time of DDR input	A, B
$t_{DDRICLR2Q1}$	Clear-to-Out Out_QR	C, D
$t_{DDRICLR2Q2}$	Clear-to-Out Out_QF	C, E
$t_{DDRIREMCLR}$	Clear Removal	C, B
$t_{DDRIRECCLR}$	Clear Recovery	C, B

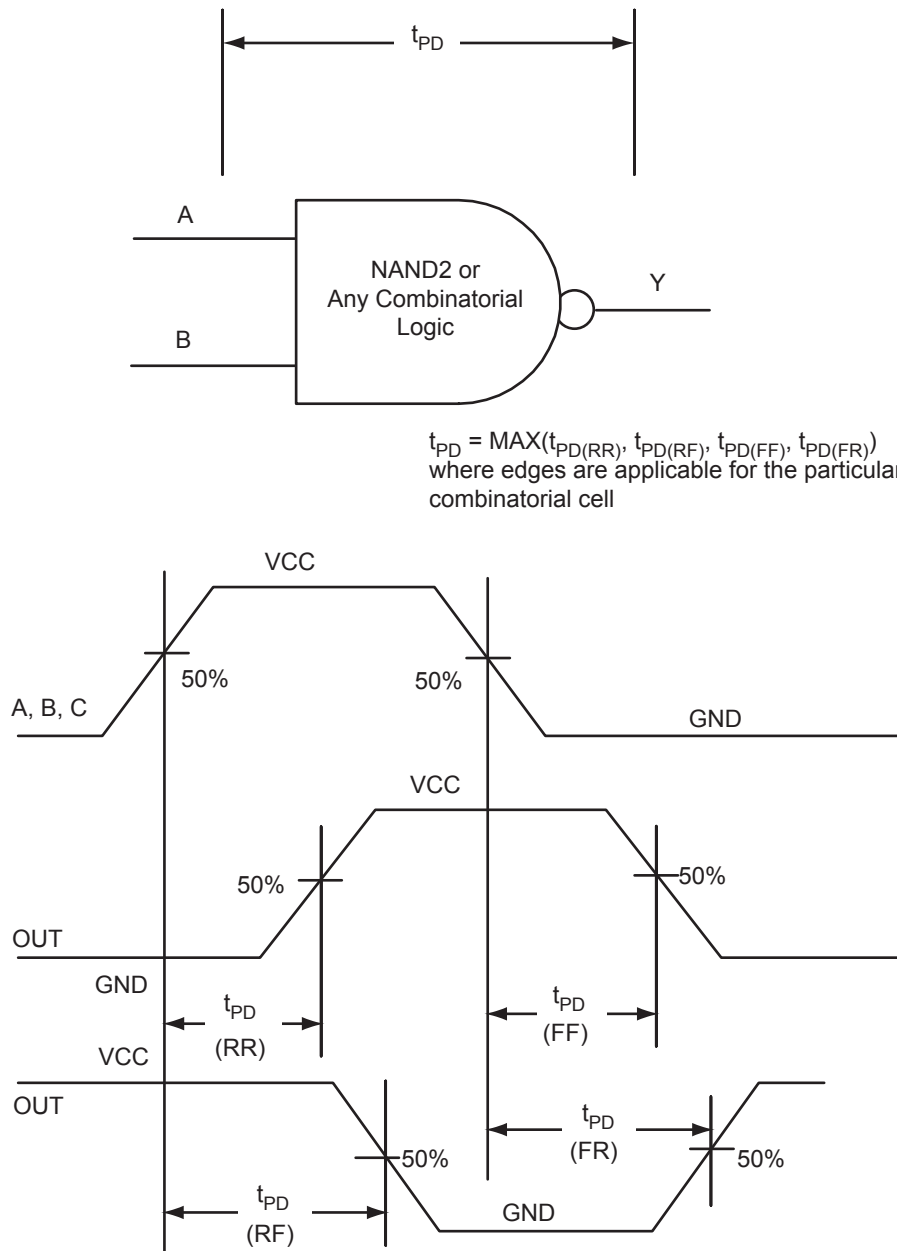


Figure 2-35 • Timing Model and Waveforms

Special Function Pins

NC

No Connect

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

DC

Do Not Connect

This pin should not be connected to any signals on the PCB. These pins should be left unconnected.

Packaging

Semiconductor technology is constantly shrinking in size while growing in capability and functional integration. To enable next-generation silicon technologies, semiconductor packages have also evolved to provide improved performance and flexibility.

Microsemi consistently delivers packages that provide the necessary mechanical and environmental protection to ensure consistent reliability and performance. Microsemi IC packaging technology efficiently supports high-density FPGAs with large-pin-count Ball Grid Arrays (BGAs), but is also flexible enough to accommodate stringent form factor requirements for Chip Scale Packaging (CSP). In addition, Microsemi offers a variety of packages designed to meet your most demanding application and economic requirements for today's embedded and mobile systems.

Related Documents

User's Guides

ProASIC3E FPGA Fabric User's Guide

http://www.microsemi.com/document-portal/doc_download/130883-proasic3e-fpga-fabric-user-s-guide

Packaging

The following documents provide packaging information and device selection for low power flash devices.

Product Catalog

http://www.microsemi.com/soc/documents/ProdCat_PIB.pdf

Lists devices currently recommended for new designs and the packages available for each member of the family. Use this document or the datasheet tables to determine the best package for your design, and which package drawing to use.

Package Mechanical Drawings

http://www.microsemi.com/document-portal/doc_download/131095-package-mechanical-drawings

This document contains the package mechanical drawings for all packages currently or previously supplied by Microsemi. Use the bookmarks to navigate to the package mechanical drawings.

Additional packaging materials: <http://www.microsemi.com/products/fpga-soc/solutions>.

FG256	
Pin Number	A3PE600 Function
A1	GND
A2	GAA0/IO00NDB0V0
A3	GAA1/IO00PDB0V0
A4	GAB0/IO01NDB0V0
A5	IO05PDB0V0
A6	IO10PDB0V1
A7	IO12PDB0V2
A8	IO16NDB0V2
A9	IO23NDB1V0
A10	IO23PDB1V0
A11	IO28NDB1V1
A12	IO28PDB1V1
A13	GBB1/IO34PDB1V1
A14	GBA0/IO35NDB1V1
A15	GBA1/IO35PDB1V1
A16	GND
B1	GAB2/IO133PDB7V1
B2	GAA2/IO134PDB7V1
B3	GNDQ
B4	GAB1/IO01PDB0V0
B5	IO05NDB0V0
B6	IO10NDB0V1
B7	IO12NDB0V2
B8	IO16PDB0V2
B9	IO20NDB1V0
B10	IO24NDB1V0
B11	IO24PDB1V0
B12	GBC1/IO33PDB1V1
B13	GBB0/IO34NDB1V1
B14	GNDQ
B15	GBA2/IO36PDB2V0
B16	IO42NDB2V0
C1	IO133NDB7V1
C2	IO134NDB7V1
C3	VMV7
C4	VCCPLA

FG256	
Pin Number	A3PE600 Function
C5	GAC0/IO02NDB0V0
C6	GAC1/IO02PDB0V0
C7	IO15NDB0V2
C8	IO15PDB0V2
C9	IO20PDB1V0
C10	IO25NDB1V0
C11	IO27PDB1V0
C12	GBC0/IO33NDB1V1
C13	VCCPLB
C14	VMV2
C15	IO36NDB2V0
C16	IO42PDB2V0
D1	IO128PDB7V1
D2	IO129PDB7V1
D3	GAC2/IO132PDB7V1
D4	VCOMPLA
D5	GNDQ
D6	IO09NDB0V1
D7	IO09PDB0V1
D8	IO13PDB0V2
D9	IO21PDB1V0
D10	IO25PDB1V0
D11	IO27NDB1V0
D12	GNDQ
D13	VCOMPLB
D14	GBB2/IO37PDB2V0
D15	IO39PDB2V0
D16	IO39NDB2V0
E1	IO128NDB7V1
E2	IO129NDB7V1
E3	IO132NDB7V1
E4	IO130PDB7V1
E5	VMV0
E6	VCCIB0
E7	VCCIB0
E8	IO13NDB0V2

FG256	
Pin Number	A3PE600 Function
E9	IO21NDB1V0
E10	VCCIB1
E11	VCCIB1
E12	VMV1
E13	GBC2/IO38PDB2V0
E14	IO37NDB2V0
E15	IO41NDB2V0
E16	IO41PDB2V0
F1	IO124PDB7V0
F2	IO125PDB7V0
F3	IO126PDB7V0
F4	IO130NDB7V1
F5	VCCIB7
F6	GND
F7	VCC
F8	VCC
F9	VCC
F10	VCC
F11	GND
F12	VCCIB2
F13	IO38NDB2V0
F14	IO40NDB2V0
F15	IO40PDB2V0
F16	IO45PSB2V1
G1	IO124NDB7V0
G2	IO125NDB7V0
G3	IO126NDB7V0
G4	GFC1/IO120PPB7V0
G5	VCCIB7
G6	VCC
G7	GND
G8	GND
G9	GND
G10	GND
G11	VCC
G12	VCCIB2

FG256	
Pin Number	A3PE600 Function
G13	GCC1/IO50PPB2V1
G14	IO44NDB2V1
G15	IO44PDB2V1
G16	IO49NSB2V1
H1	GFB0/IO119NPB7V0
H2	GFA0/IO118NDB6V1
H3	GFB1/IO119PPB7V0
H4	VCOMPLF
H5	GFC0/IO120NPB7V0
H6	VCC
H7	GND
H8	GND
H9	GND
H10	GND
H11	VCC
H12	GCC0/IO50NPB2V1
H13	GCB1/IO51PPB2V1
H14	GCA0/IO52NPB3V0
H15	VCOMPLC
H16	GCB0/IO51NPB2V1
J1	GFA2/IO117PSB6V1
J2	GFA1/IO118PDB6V1
J3	VCCPLF
J4	IO116NDB6V1
J5	GFB2/IO116PDB6V1
J6	VCC
J7	GND
J8	GND
J9	GND
J10	GND
J11	VCC
J12	GCB2/IO54PPB3V0
J13	GCA1/IO52PPB3V0
J14	GCC2/IO55PPB3V0
J15	VCCPLC
J16	GCA2/IO53PSB3V0

FG256	
Pin Number	A3PE600 Function
K1	GFC2/IO115PSB6V1
K2	IO113PPB6V1
K3	IO112PDB6V1
K4	IO112NDB6V1
K5	VCCIB6
K6	VCC
K7	GND
K8	GND
K9	GND
K10	GND
K11	VCC
K12	VCCIB3
K13	IO54NPB3V0
K14	IO57NPB3V0
K15	IO55NPB3V0
K16	IO57PPB3V0
L1	IO113NPB6V1
L2	IO109PPB6V0
L3	IO108PDB6V0
L4	IO108NDB6V0
L5	VCCIB6
L6	GND
L7	VCC
L8	VCC
L9	VCC
L10	VCC
L11	GND
L12	VCCIB3
L13	GDB0/IO66NPB3V1
L14	IO60NDB3V1
L15	IO60PDB3V1
L16	IO61PDB3V1
M1	IO109NPB6V0
M2	IO106NDB6V0
M3	IO106PDB6V0
M4	GEC0/IO104NPB6V0

FG256	
Pin Number	A3PE600 Function
M5	VMV5
M6	VCCIB5
M7	VCCIB5
M8	IO84NDB5V0
M9	IO84PDB5V0
M10	VCCIB4
M11	VCCIB4
M12	VMV3
M13	VCCPLD
M14	GDB1/IO66PPB3V1
M15	GDC1/IO65PDB3V1
M16	IO61NDB3V1
N1	IO105PDB6V0
N2	IO105NDB6V0
N3	GEC1/IO104PPB6V0
N4	VCOMPLE
N5	GNDQ
N6	GEA2/IO101PPB5V2
N7	IO92NDB5V1
N8	IO90NDB5V1
N9	IO82NDB5V0
N10	IO74NDB4V1
N11	IO74PDB4V1
N12	GNDQ
N13	VCOMPLD
N14	VJTAG
N15	GDC0/IO65NDB3V1
N16	GDA1/IO67PDB3V1
P1	GEB1/IO103PDB6V0
P2	GEB0/IO103NDB6V0
P3	VMV6
P4	VCCPLE
P5	IO101NPB5V2
P6	IO95PPB5V1
P7	IO92PDB5V1
P8	IO90PDB5V1

FG484	
Pin Number	A3PE600 Function
A1	GND
A2	GND
A3	VCCIB0
A4	IO06NDB0V1
A5	IO06PDB0V1
A6	IO08NDB0V1
A7	IO08PDB0V1
A8	IO11PDB0V1
A9	IO17PDB0V2
A10	IO18NDB0V2
A11	IO18PDB0V2
A12	IO22PDB1V0
A13	IO26PDB1V0
A14	IO29NDB1V1
A15	IO29PDB1V1
A16	IO31NDB1V1
A17	IO31PDB1V1
A18	IO32NDB1V1
A19	NC
A20	VCCIB1
A21	GND
A22	GND
AA1	GND
AA2	VCCIB6
AA3	NC
AA4	IO98PDB5V2
AA5	IO96NDB5V2
AA6	IO96PDB5V2
AA7	IO86NDB5V0
AA8	IO86PDB5V0
AA9	IO85PDB5V0
AA10	IO85NDB5V0
AA11	IO78PPB4V1
AA12	IO79NDB4V1
AA13	IO79PDB4V1
AA14	NC

FG484	
Pin Number	A3PE600 Function
AA15	NC
AA16	IO71NDB4V0
AA17	IO71PDB4V0
AA18	NC
AA19	NC
AA20	NC
AA21	VCCIB3
AA22	GND
AB1	GND
AB2	GND
AB3	VCCIB5
AB4	IO97NDB5V2
AB5	IO97PDB5V2
AB6	IO93NDB5V1
AB7	IO93PDB5V1
AB8	IO87NDB5V0
AB9	IO87PDB5V0
AB10	NC
AB11	NC
AB12	IO75NDB4V1
AB13	IO75PDB4V1
AB14	IO72NDB4V0
AB15	IO72PDB4V0
AB16	IO73NDB4V0
AB17	IO73PDB4V0
AB18	NC
AB19	NC
AB20	VCCIB4
AB21	GND
AB22	GND
B1	GND
B2	VCCIB7
B3	NC
B4	IO03NDB0V0
B5	IO03PDB0V0
B6	IO07NDB0V1

FG484	
Pin Number	A3PE600 Function
B7	IO07PDB0V1
B8	IO11NDB0V1
B9	IO17NDB0V2
B10	IO14PDB0V2
B11	IO19PDB0V2
B12	IO22NDB1V0
B13	IO26NDB1V0
B14	NC
B15	NC
B16	IO30NDB1V1
B17	IO30PDB1V1
B18	IO32PDB1V1
B19	NC
B20	NC
B21	VCCIB2
B22	GND
C1	VCCIB7
C2	NC
C3	NC
C4	NC
C5	GND
C6	IO04NDB0V0
C7	IO04PDB0V0
C8	VCC
C9	VCC
C10	IO14NDB0V2
C11	IO19NDB0V2
C12	NC
C13	NC
C14	VCC
C15	VCC
C16	NC
C17	NC
C18	GND
C19	NC
C20	NC

FG484		FG484		FG484	
Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function
C21	IO94PPB2V1	E13	IO58NDB1V2	G5	IO297PDB7V2
C22	VCCIB2	E14	IO58PDB1V2	G6	GAC2/IO307PDB7V4
D1	IO293PDB7V2	E15	GBC1/IO79PDB1V4	G7	VCOMPLA
D2	IO303NDB7V3	E16	GBB0/IO80NDB1V4	G8	GNDQ
D3	IO305NDB7V3	E17	GNDQ	G9	IO26NDB0V3
D4	GND	E18	GBA2/IO82PDB2V0	G10	IO26PDB0V3
D5	GAA0/IO00NDB0V0	E19	IO86NDB2V0	G11	IO36PDB0V4
D6	GAA1/IO00PDB0V0	E20	GND	G12	IO42PDB1V0
D7	GAB0/IO01NDB0V0	E21	IO90NDB2V1	G13	IO50PDB1V1
D8	IO20PDB0V2	E22	IO98PDB2V2	G14	IO60NDB1V2
D9	IO22PDB0V2	F1	IO299NPB7V3	G15	GNDQ
D10	IO30PDB0V3	F2	IO301NDB7V3	G16	VCOMPLB
D11	IO38NDB0V4	F3	IO301PDB7V3	G17	GBB2/IO83PDB2V0
D12	IO52NDB1V1	F4	IO308NDB7V4	G18	IO92PDB2V1
D13	IO52PDB1V1	F5	IO309NDB7V4	G19	IO92NDB2V1
D14	IO66NDB1V3	F6	VMV7	G20	IO102PDB2V2
D15	IO66PDB1V3	F7	VCCPLA	G21	IO102NDB2V2
D16	GBB1/IO80PDB1V4	F8	GAC0/IO02NDB0V0	G22	IO105NDB2V2
D17	GBA0/IO81NDB1V4	F9	GAC1/IO02PDB0V0	H1	IO286PSB7V1
D18	GBA1/IO81PDB1V4	F10	IO32NDB0V3	H2	IO291NPB7V2
D19	GND	F11	IO32PDB0V3	H3	VCC
D20	IO88PDB2V0	F12	IO44PDB1V0	H4	IO295NDB7V2
D21	IO90PDB2V1	F13	IO50NDB1V1	H5	IO297NDB7V2
D22	IO94NPB2V1	F14	IO60PDB1V2	H6	IO307NDB7V4
E1	IO293NDB7V2	F15	GBC0/IO79NDB1V4	H7	IO287PDB7V1
E2	IO299PPB7V3	F16	VCCPLB	H8	VMV0
E3	GND	F17	VMV2	H9	VCCIB0
E4	GAB2/IO308PDB7V4	F18	IO82NDB2V0	H10	VCCIB0
E5	GAA2/IO309PDB7V4	F19	IO86PDB2V0	H11	IO36NDB0V4
E6	GNDQ	F20	IO96PDB2V1	H12	IO42NDB1V0
E7	GAB1/IO01PDB0V0	F21	IO96NDB2V1	H13	VCCIB1
E8	IO20NDB0V2	F22	IO98NDB2V2	H14	VCCIB1
E9	IO22NDB0V2	G1	IO289NDB7V1	H15	VMV1
E10	IO30NDB0V3	G2	IO289PDB7V1	H16	GBC2/IO84PDB2V0
E11	IO38PDB0V4	G3	IO291PPB7V2	H17	IO83NDB2V0
E12	IO44NDB1V0	G4	IO295PDB7V2	H18	IO100NDB2V2

FG896		FG896		FG896	
Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function
J5	IO295NDB7V2	K11	IO04PPB0V0	L17	VCC
J6	IO299NDB7V3	K12	VCCIB0	L18	VCC
J7	VCCIB7	K13	VCCIB0	L19	VCC
J8	VCCPLA	K14	VCCIB0	L20	VCC
J9	VCC	K15	VCCIB0	L21	IO78NPB1V4
J10	IO04NPB0V0	K16	VCCIB1	L22	IO104NPB2V2
J11	IO18NDB0V2	K17	VCCIB1	L23	IO98NDB2V2
J12	IO20NDB0V2	K18	VCCIB1	L24	IO98PDB2V2
J13	IO20PDB0V2	K19	VCCIB1	L25	IO87PDB2V0
J14	IO32NDB0V3	K20	IO76PPB1V4	L26	IO87NDB2V0
J15	IO32PDB0V3	K21	VCC	L27	IO97PDB2V1
J16	IO42PDB1V0	K22	IO78PPB1V4	L28	IO101PDB2V2
J17	IO44NDB1V0	K23	IO88NDB2V0	L29	IO103PDB2V2
J18	IO44PDB1V0	K24	IO88PDB2V0	L30	IO119NDB3V0
J19	IO54NDB1V1	K25	IO94PDB2V1	M1	IO282NDB7V1
J20	IO54PDB1V1	K26	IO94NDB2V1	M2	IO282PDB7V1
J21	IO76NPB1V4	K27	IO85PDB2V0	M3	IO292NDB7V2
J22	VCC	K28	IO85NDB2V0	M4	IO292PDB7V2
J23	VCCPLB	K29	IO93PDB2V1	M5	IO283NDB7V1
J24	VCCIB2	K30	IO93NDB2V1	M6	IO285PDB7V1
J25	IO90PDB2V1	L1	IO286NDB7V1	M7	IO287PDB7V1
J26	IO90NDB2V1	L2	IO286PDB7V1	M8	IO289PDB7V1
J27	GBB2/IO83PDB2V0	L3	IO298NDB7V3	M9	IO289NDB7V1
J28	IO83NDB2V0	L4	IO298PDB7V3	M10	VCCIB7
J29	IO91PDB2V1	L5	IO283PDB7V1	M11	VCC
J30	IO91NDB2V1	L6	IO291NDB7V2	M12	GND
K1	IO288NDB7V1	L7	IO291PDB7V2	M13	GND
K2	IO288PDB7V1	L8	IO293PDB7V2	M14	GND
K3	IO304NDB7V3	L9	IO293NDB7V2	M15	GND
K4	IO304PDB7V3	L10	IO307NPB7V4	M16	GND
K5	GAB2/IO308PDB7V4	L11	VCC	M17	GND
K6	IO308NDB7V4	L12	VCC	M18	GND
K7	IO301PDB7V3	L13	VCC	M19	GND
K8	IO301NDB7V3	L14	VCC	M20	VCC
K9	GAC2/IO307PPB7V4	L15	VCC	M21	VCCIB2
K10	VCC	L16	VCC	M22	NC

Revision	Changes	Page														
Revision 9 (Aug 2009) Product Brief v1.2	All references to speed grade –F have been removed from this document.	N/A														
DC and Switching Characteristics v1.3	The "Pro I/Os with Advanced I/O Standards" section was revised to add definitions of hot-swap and cold-sparing.	1-6														
	3.3 V LVCMOS and 1.2 V LVCMOS Wide Range support was added to the datasheet. This affects all tables that contained 3.3 V LVCMOS and 1.2 V LVCMOS data.	N/A														
	IIL and IIH input leakage current information was added to all "Minimum and Maximum DC Input and Output Levels" tables.	N/A														
	–F was removed from the datasheet. The speed grade is no longer supported.	N/A														
	In the Table 2-2 • Recommended Operating Conditions ¹ "3.0 V DC supply voltage" and note 4 are new.	2-2														
	The Table 2-4 • Overshoot and Undershoot Limits ¹ table was updated.	2-3														
	The Table 2-6 • Temperature and Voltage Derating Factors for Timing Delays table was updated.	2-5														
	There are new parameters and data was updated in the Table 2-99 • RAM4K9 table.	2-76														
	There are new parameters and data was updated in the Table 2-100 • RAM512X18 table.	2-77														
Revision 8 (Feb 2008) Product Brief v1.1	Table 1-2 • ProASIC3E FPGAs Package Sizes Dimensions is new.	1-II														
Revision 7 (Jun 2008) DC and Switching Characteristics v1.2	The title of Table 2-4 • Overshoot and Undershoot Limits ¹ was modified to remove "as measured on quiet I/Os." Table note 2 was revised to remove "estimated SSO density over cycles." Table note 3 was deleted.	2-3														
	Table 2-78 • LVDS Minimum and Maximum DC Input and Output Levels was updated.	2-50														
Revision 6 (Jun 2008)	The A3PE600 "FG484" table was missing G22. The pin and its function were added to the table.	4-27														
Revision 5 (Jun 2008) Packaging v1.4	The naming conventions changed for the following pins in the "FG484" for the A3PE600: <table><tr><th>Pin Number</th><th>New Function Name</th></tr><tr><td>J19</td><td>IO45PPB2V1</td></tr><tr><td>K20</td><td>IO45NPB2V1</td></tr><tr><td>M2</td><td>IO114NPB6V1</td></tr><tr><td>N1</td><td>IO114PPB6V1</td></tr><tr><td>N4</td><td>GFC2/IO115PPB6V1</td></tr><tr><td>P3</td><td>IO115NPB6V1</td></tr></table>	Pin Number	New Function Name	J19	IO45PPB2V1	K20	IO45NPB2V1	M2	IO114NPB6V1	N1	IO114PPB6V1	N4	GFC2/IO115PPB6V1	P3	IO115NPB6V1	4-22
Pin Number	New Function Name															
J19	IO45PPB2V1															
K20	IO45NPB2V1															
M2	IO114NPB6V1															
N1	IO114PPB6V1															
N4	GFC2/IO115PPB6V1															
P3	IO115NPB6V1															
Revision 4 (Apr 2008) Product Brief v1.0	The product brief portion of the datasheet was divided into two sections and given a version number, starting at v1.0. The first section of the document includes features, benefits, ordering information, and temperature and speed grade offerings. The second section is a device family overview.	N/A														
Packaging v1.3	The "FG324" package diagram was replaced.	4-12														